





an Open Access Journal by MDPI

Digital Trustworthiness: Cybersecurity, Privacy and Resilience

Guest Editors:

Dr. Muath Obaidat

Computer Science Department, City University of New York, New York, NY 10019, USA

Prof. Dr. Thaier Hayajneh

Fordham Center for Cybersecurity, Fordham University, New York, NY 10023, USA

Dr. Eman Hammad

Computer Science and Information Systems, Texas A&M University, College Station, TX 77843, USA

Deadline for manuscript submissions:

closed (31 August 2022)

Message from the Guest Editors

Dear Colleagues,

This Special Issue on "Digital trustworthiness: cybersecurity, privacy and resilience" solicits articles in multiple domains and topics including but not limited to the following:

- Cybersecurity: formal methods;
- Cryptography and cryptanalysis: quantum-safe
- Cybersecurity and cybercrime
- Wireless and mobile networks security
- Critical infrastructures security
- Privacy and anonymity
- IoT and mobile devices security
- Digital forensics
- Cybersecurity and privacy laws and ethics
- Cloud, fog and edge computing security
- Trust/blockchain for systems security
- Machine learning for security



Specialsue







an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank: JCR - Q2 (Physics, Applied) / CiteScore - Q2 (Control and Systems

Engineering)

Contact Us